

Notice of References Cited

Application/Control No.

09/927,011

Applicant(s)/Patent Under

Reexamination

BARTENSTEIN ET AL.

Examiner

R. Stephen Dildine

Art Unit

2133

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0184580 A1	12-2002	Archibald et al.	714/719
	B	US-5,912,901 A	06-1999	Adams et al.	714/733
	C	US-5,991,215 A	11-1999	Brunelle, Steven J.	365/201
	D	US-6,636,998 B1	10-2003	Lee et al.	714/735
	E	US-6,195,771 B1	02-2001	Tanabe et al.	714/718
	F	US-5,954,830 A	09-1999	Ternullo, Jr., Luigi	714/718
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	TDB-ACC-NO: NNRD439133; A method for scan based memory test to supplement built-in self-test; IBM Technical Disclosure Bulletin, Issue Number 439; November 2000, UK; page 2015
	V	Matsumura, T.; An efficient test method for embedded multi-port RAM with BIST circuitry; <input type="checkbox"/> Memory Technology, Design and Testing, 1995., Records of the 1995 IEEE International Workshop on , 7-8 Aug. 1995; Pages:62 - 67
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.